Erratum

Investigation of heteroepitaxial diamond films by atomic force and scanning tunneling microscopy

K. Schiffmann, X. Jiang

Appl. Phys. A **59**, 17–22 (1994)

In this contribution, several wrong numerical values for the crystal tilt have been published in the text on pages 17, 20, 22, and in Fig. 5a–d on page 22.

Page 17:

Besides the good macroscopic crystal morphology a statistical tilt up to $\pm 5.2^\circ$ of the oriented crystallites has been found relative to the silicon substrates.

Fig. 5a–d. Distributions of tilt angles of the (001) crystal surface of heteroepitaxial diamond crystallites relative to its silicon substrate. (a) and (b): tilt for sample 1 in [100] and [110] direction;

(c) and (d): tilt for sample 2 in [100] and [110] direction. Mean width of tilt distribution for sample 1 is $\pm 4.3^\circ$, while for sample 2 it is reduced to $\pm 3.4^\circ$

It should read:

Besides the good macroscopic crystal morphology a statistical tilt up to $\pm 4.3^\circ$ of the oriented crystallites has been found relative to the silicon substrates.

Page 20:

Sample 1 has a FWHM of 10.4° , while sample 2 results in a FWHM of 8.0° .

It should read:

Sample 1 has a FWHM of 8.6° , while sample 2 results in a FWHM of 6.7° .

Page 22:

It has been found that, besides the good macroscopical crystal morphology, a statistical tilting of the oriented crystallites exists up to $\pm 5.2^\circ$ relative to the silicon substrates.

It should read:

It has been found that, besides the good macroscopic crystal morphology, a statistical tilting of the oriented crystallites exists up to $\pm 4.3^\circ$ relative to the silicon substrates.

Figure 5a–d should be replaced by the figure on page.